



DMN3022LDG

30V SYNCHRONOUS N-CHANNEL ENHANCEMENT MODE MOSFET PowerDI3333-8 (Type D)

Product Summary

Device	BV _{DSS}	R _{DS(ON)} Max
Q1	30V	$22m\Omega$ @ $V_{GS} = 5V$, $I_D = 10A$
Q2	30V	$8m\Omega @ V_{GS} = 5V, I_D = 10A$

Features and Benefits

- 100% Unclamped Inductive Switch (UIS) Test in Production
- Low On-Resistance
- Low Input Capacitance
- · Fast Switching Speed
- Lead-Free Finish; RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)

Description and Applications

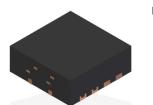
This new generation MOSFET is designed to minimize the on-state resistance (R_{DS(ON)}) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

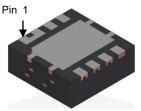
PowerDI3333-8 (Type D)

- DC-DC Converters
- Power Management Functions
- Analog Switch

Mechanical Data

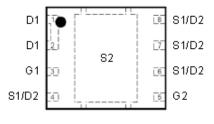
- Case: PowerDI[®]3333-8 (Type D)
- Case Material: Molded Plastic, "Green" Molding Compound.
 UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Terminals: Finish Matte Tin Annealed over Copper Leadframe.
 Solderable per MIL-STD-202, Method 208 ⁽³⁾
- Weight: 0.044 grams (Approximate)





Top View

Bottom View



Top View Pin Configuration

Ordering Information (Note 4)

Part Number	Case	Packaging		
DMN3022LDG-7	PowerDI3333-8 (Type D)	1,000/Tape & Reel		
DMN3022LDG-13	PowerDI3333-8 (Type D)	3,000/Tape & Reel		

Notes:

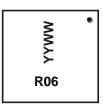
- 1. EU Directive 2002/95/EC (RoHS), 2011/65/EU (RoHS 2) & 2015/863/EU (RoHS 3) compliant. All applicable RoHS exemptions applied.
- 2. See https://www.diodes.com/quality/lead-free/ for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.

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4. For packaging details, go to our website at https://www.diodes.com/design/support/packaging/diodes-packaging/

Marking Information



R06 = Product Type Marking Code YYWW = Date Code Marking YY = Last Two Digits of Year (ex: 18 = 2018) WW = Week Code (01 to 53)



Maximum Ratings (@ $T_A = +25$ °C, unless otherwise specified.)

Characteristic	Symbol	Q1	Q2	Unit	
Drain-Source Voltage		V_{DSS}	30		V
Gate-Source Voltage	V _{GSS}	±10		V	
Continuous Prais Correct @ V 5V	$T_C = +25$ °C $T_C = +70$ °C	I _D	15 12		А
Continuous Drain Current @ V _{GS} = 5V	T _A = +25°C T _A = +70°C	I _D	7.6 6.1		А
Pulsed Drain Current (10µs Pulse, Duty Cycle = 1%)	I _{DM}	50	100	Α	
Avalanche Current (Note 6) L = 0.1mH		I _{AS}	24	43	Α
Avalanche Energy (Note 6) L = 0.1mH		Eas	28	92	mJ

Thermal Characteristics (@T_A = +25°C, unless otherwise specified.)

Characteristic		Symbol	Value	Unit	
Total Power Dissipation	$T_A = +25^{\circ}C$	ס	1.96	W	
Total Fower Dissipation	$T_A = +70^{\circ}C$	P_{D}	1.25	VV	
Thermal Resistance, Junction to Ambient (Note 5)	Steady State	D	64	°C/W	
mermai Resistance, Junction to Ambient (Note 5)	t < 10s	$R_{\theta JA}$	36		
Thermal Resistance, Junction to Case (Note 5)	R _e JC	8.7			
Operating and Storage Temperature Range	T _{J,} T _{STG}	-55 to +150	°C		

Electrical Characteristics Q1 (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 7)							
Drain-Source Breakdown Voltage	BV _{DSS}	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$	
Zero Gate Voltage Drain Current	I _{DSS}	_	_	1	μΑ	$V_{DS} = 20V, V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 10V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 7)							
Gate Threshold Voltage	V _{GS(TH)}	1	1.4	2.1	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	
Static Drain-Source On-Resistance	R _{DS(ON)}	_	16	22	mΩ	$V_{GS} = 5V, I_D = 10A$	
Forward Transfer Admittance	Y _{FS}	_	17	_	S	$V_{DS} = 5V, I_{D} = 8A$	
Diode Forward Voltage	V_{SD}	_	0.84	1	V	$V_{GS} = 0V, I_{S} = 8A$	
DYNAMIC CHARACTERISTICS (Note 8)							
Input Capacitance	C _{iss}	_	370	481		V _{DS} = 15V, V _{GS} = 0V, f = 1.0MHz	
Output Capacitance	Coss	_	176	228	pF		
Reverse Transfer Capacitance	C _{rss}	_	8.2	10.6			
Gate Resistance	R_{G}	_	2.5	6.5	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$	
Total Gate Charge (V _{GS} = 4.5V)	Q_G	_	2.8	3.7		V _{DS} = 15V, I _D = 8A	
Total Gate Charge at V _{TH}	Q _{G(TH)}	_	0.35	_	nC		
Gate-Source Charge	Q_{GS}	_	0.6	_	IIC		
Gate-Drain Charge	Q_{GD}	_	0.5	_			
Turn-On Delay Time	t _{D(ON)}	_	4.5	6.7		$V_{DD} = 15V, V_{GS} = 4.5V,$ $I_{D} = 8A, R_{G} = 2\Omega$	
Turn-On Rise Time	t _R	_	1.8	_			
Turn-Off Delay Time	t _{D(OFF)}	_	7.2	10.8	ns		
Turn-Off Fall Time	t _F	_	1.9		1		
Reverse Recovery Time	t _{RR}	_	11.5		ns		
Reverse Recovery Charge	Q _{RR}	_	6.9	_	nC	$I_F = 8A$, di/dt = 300A/ μ s	

Notes

- 5. Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
- 6. I_{AS} and E_{AS} ratings are based on low frequency and duty cycles to keep T_J = +25°C.
- 7. Short duration pulse test used to minimize self-heating effect.
- 8. Guaranteed by design. Not subject to product testing.

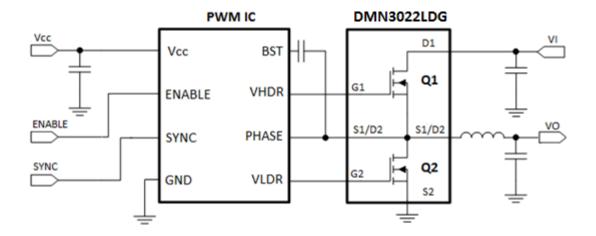


Electrical Characteristics Q2 (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition		
OFF CHARACTERISTICS (Note 7)								
Drain-Source Breakdown Voltage	BV _{DSS}	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$		
Zero Gate Voltage Drain Current T _J = +25°C	I _{DSS}	_	_	1.0	μA	$V_{DS} = 20V$, $V_{GS} = 0V$		
Gate-Source Leakage	I_{GSS}	_	_	±100	nA	$V_{GS} = \pm 10V, V_{DS} = 0V$		
ON CHARACTERISTICS (Note 7)								
Gate Threshold Voltage	$V_{GS(TH)}$	0.8	0.96	1.2	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		
Static Drain-Source On-Resistance	R _{DS(ON)}	_	6.4	8	mΩ	$V_{GS} = 5V, I_D = 10A$		
Forward Transfer Admittance	Y _{FS}	_	33	_	S	$V_{DS} = 5V, I_{D} = 8A$		
Diode Forward Voltage	V_{SD}	_	0.78	1	V	$V_{GS} = 0V, I_{S} = 8A$		
DYNAMIC CHARACTERISTICS (Note 8)	DYNAMIC CHARACTERISTICS (Note 8)							
Input Capacitance	C _{iss}	_	766	996	pF	V _{DS} = 15V, V _{GS} = 0V, f = 1.0MHz		
Output Capacitance	Coss	_	441	573	pF			
Reverse Transfer Capacitance	C_{rss}	_	19	25	pF	1 = 1.000112		
Gate Resistance	R_{G}	_	0.69	1.5	Ω	$V_{DS} = 0V$, $V_{GS} = 0V$, $f = 1MHz$		
Total Gate Charge (V _{GS} = 4.5V)	Q_{G}	_	6.1	8	nC			
Total Gate Charge at V _{TH}	Q _{G(TH)}	_	0.47	_	nC	\/ 15\/ 0A		
Gate-Source Charge	Q _{GS}	_	0.8	_	nC	$V_{DS} = 15V, I_{D} = 8A$		
Gate-Drain Charge	Q_{GD}	_	1.1	_	nC			
Turn-On Delay Time	t _{D(ON)}	_	5.6	8.4	ns	V _{DD} = 15V, V _{GS} = 4.5V,		
Turn-On Rise Time	t _R	_	2.5	_	ns			
Turn-Off Delay Time	t _{D(OFF)}	_	11.7	17.5	ns	$I_D = 8A, R_G = 2\Omega$		
Turn-Off Fall Time	t _F		2.4		ns			
Reverse Recovery Time	t _{RR}	_	27.9	_	ns	1 9A di/dt 200A/us		
Reverse Recovery Charge	Q_{RR}	_	9.9	_	nC	$I_F = 8A$, di/dt = 300A/ μ s		

7. Short duration pulse test used to minimize self-heating effect. 8. Guaranteed by design. Not subject to product testing. Notes:

Typical Circuit





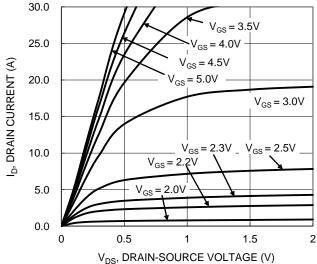


Figure 1. Q1 Typical Output Characteristic

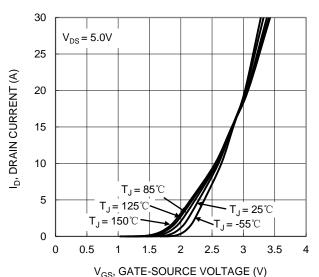


Figure 3. Q1 Typical Transfer Characteristic

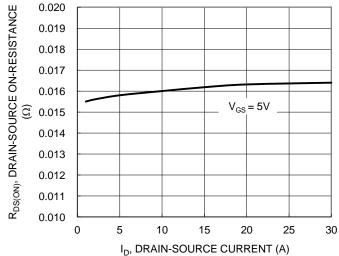
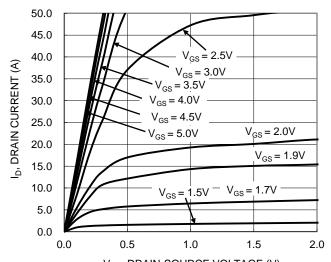


Figure 5. Q1 Typical On-Resistance vs. Drain Current and Gate Voltage



 $\rm V_{DS}$, DRAIN-SOURCE VOLTAGE (V) Figure 2. Q2 Typical Output Characteristic

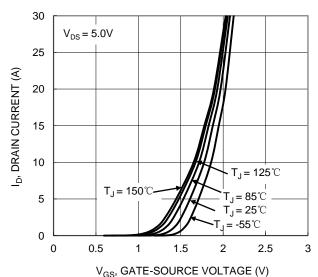


Figure 4. Q2 Typical Transfer Characteristic

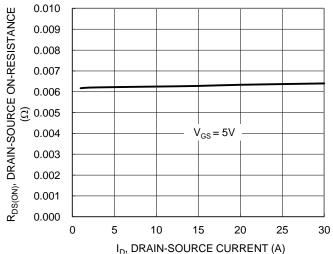
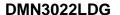
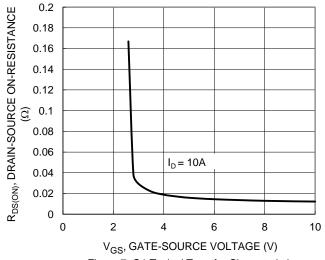


Figure 6. Q2 Typical On-Resistance vs. Drain Current and Gate Voltage







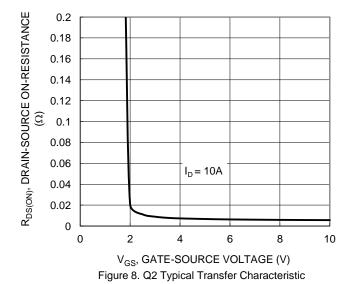
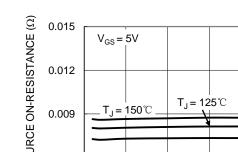
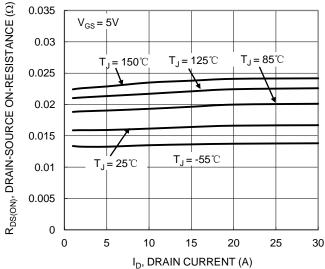


Figure 7. Q1 Typical Transfer Characteristic





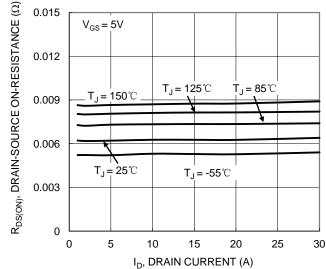
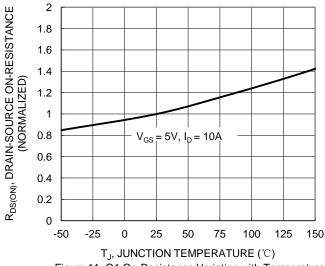


Figure 9. Q1 Typical On-Resistance vs. Drain Current and Temperature

Figure 10. Q2 Typical On-Resistance vs. Drain Current and Temperature



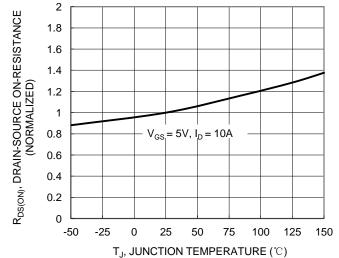


Figure 11. Q1 On-Resistance Variation with Temperature

Figure 12. Q2 On-Resistance Variation with Temperature





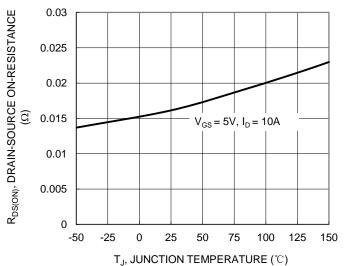


Figure 13. Q1 On-Resistance Variation with Temperature

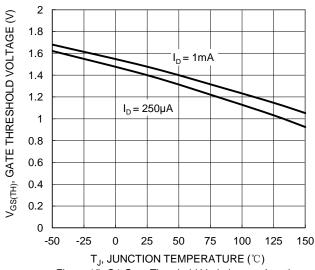


Figure 15. Q1 Gate Threshold Variation vs. Junction Temperature

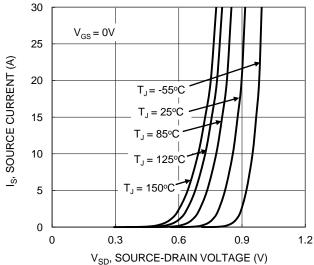


Figure 17. Q1 Diode Forward Voltage vs. Current

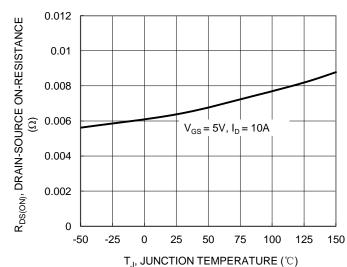


Figure 14. Q2 On-Resistance Variation with Temperature

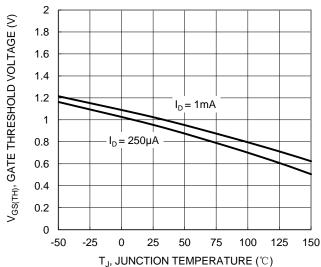


Figure 16. Q2 Gate Threshold Variation vs. Junction Temperature

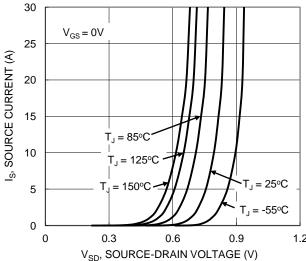


Figure 18. Q2 Diode Forward Voltage vs. Current



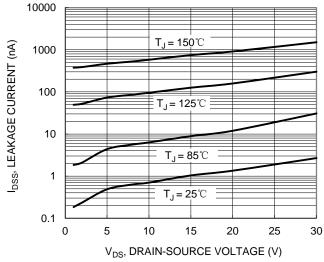


Figure 19. Q1 Typical Drain-Source Leakage Current vs. Voltage

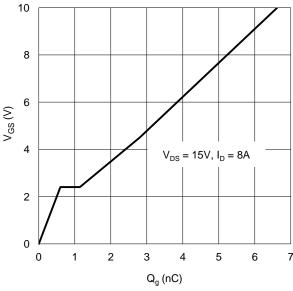
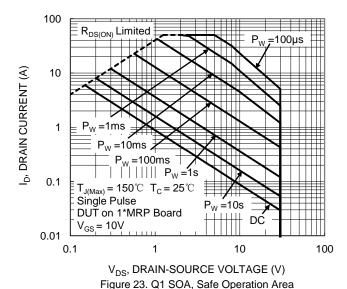


Figure 21. Q1 Gate Charge



100000 T_J = 150°C 10000 I_{DSS}, LEAKAGE CURRENT (nA) 1000 T_{.1}= 125℃ 100 T₁ = 85°C 10 T₁= 25° 0.1 10 0 15 20 25 30 V_{DS}, DRAIN-SOURCE VOLTAGE (V)

Figure 20. Q2 Typical Drain-Source Leakage Current vs. Voltage

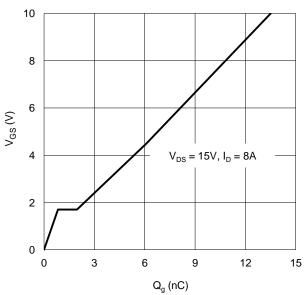


Figure 22. Q2 Gate Charge

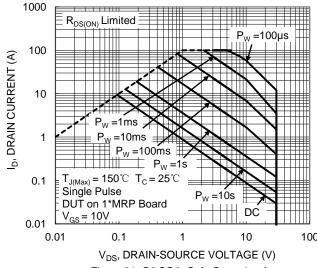


Figure 24. Q2 SOA, Safe Operation Area



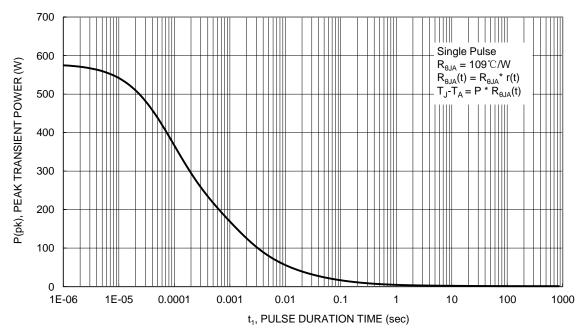


Figure 25. Single Pulse Maximum Power Dissipation

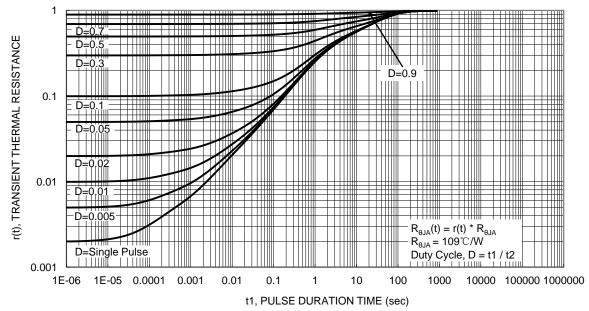


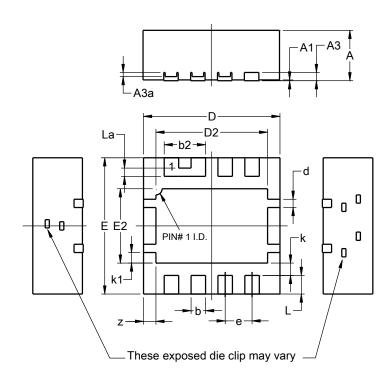
Figure 26. Transient Thermal Resistance



Package Outline Dimensions

Please see http://www.diodes.com/package-outlines.html for the latest version.

PowerDI3333-8 (Type D)

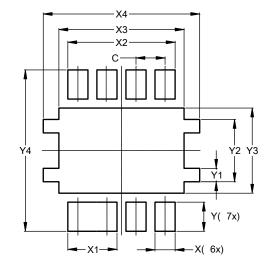


PowerDI3333-8 (Type D)					
Dim	Min	Max	Тур		
Α	1.17	1.23	1.20		
A1	0.00	0.05	0.02		
A3	0.15	0.25	0.20		
A3a	0.05	0.15	0.10		
b	0.30	0.40	0.35		
b2	0.95	1.05	1.00		
D	3.20	3.40	3.30		
D2	2.65	2.75	2.70		
E	3.20	3.40	3.30		
E2	1.75	1.85	1.80		
d	0.15	0.25	0.20		
е			0.65		
k			0.30		
k1	0.21	0.31	0.26		
L	0.40	0.50	0.45		
La	0.15	0.25	0.20		
Z	0.25	0.35	0.30		
All Dimensions in mm					

Suggested Pad Layout

Please see http://www.diodes.com/package-outlines.html for the latest version.

PowerDI3333-8 (Type D)



Dimensions	Value
Dillielisions	(in mm)
C	0.650
Х	0.450
X1	1.100
X2	2.400
Х3	2.800
X4	3.500
Y	0.650
Y1	0.300
Y2	1.390
Y3	1.900
Y4	3.600



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